

Docket No.: 50099-238

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
	:	
Shigenobu MAEDA, et al.	:	Confirmation Number:
	:	
Serial No.: Divisional of Appl. No. 09/988,593	:	Group Art Unit:
	:	
Filed: December 31, 2003	:	Examiner:
	:	
For: SEMICONDUCTOR DEVICE HAVING IMPURITY REGION UNDER ISOLATION REGION (AS AMENDED)		

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The references were cited by or submitted to the U.S. Patent and Trademark Office in parent application Serial No. 09/988,593, filed November 20, 2001, which is relied upon for an

Serial No.: Divisional of Appl. No.

earlier filing date under 35 USC 120. Thus, copies of these references are not attached. 37 CFR 1.98(d).

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

A handwritten signature in black ink, appearing to read 'S. A. Becker', with the number '42984' written below it.

Stephen A. Becker
Registration No. 26,527

600 13th Street, N.W.
Washington, DC 20005-3096
(202) 756-8000 SAB:prg
Facsimile: (202) 756-8087
Date: December 31, 2003

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 50099-238		SERIAL NO. Divisional f Appl. N 09/988,593	
				APPLICANT Shigenobu MAEDA, et al.			
				FILING DATE December 31, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US	6,410,369	06/2002	Flaker et al.		
		US	6,483,165	11/2002	Ooishi et al.		
		US	U.S.S.N. 09/466,934	12/20/1999			
		US	U.S.S.N. 09/639,953	08/17/2000			
		US	U.S.S.N. 09/677,881	10/03/2000			
		US					
		US					
		US					
		US					
		US					
		US					
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4 -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		Hirano, et al., "Bulk-Layout-Compatible 0.18 μ m SOI-COS Technology Using Body-Fixed Partial Trench Isolation (PTI)" Proceedings of 1999 IEEE International SOI Conference, October 1999, pages, 131 - 132					
		Maeda, et al., "Analysis of Delay Time Instability According to the Operating Frequency in Field Shield Isolated SOI Circuits" Proceeding of IEEE Transactions of Electron Devices, Vol. 45, No.7, July 1998, pages 1479 - 1486					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.